

<b>Notice of References Cited</b>	Application/Control No. 10/810,445		Applicant(s)/Patent Under Reexamination LEHE ET AL.	
	Examiner Victor X. Nguyen		Art Unit 3734	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,059,183	10-1991	Semrad, Neal	604/158
*	B	US-6,152,946	11-2000	Broome et al.	606/200
*	C	US-5,662,703	09-1997	Yurek et al.	623/1.12
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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